



**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant: Hideharu Ozaki

Examiner: James C. Kerveros

Serial No.: 10/063,472

Art Unit: 2133

Filed: April 26, 2002

Docket: 15483

For: SEMICONDUCTOR INTEGRATED  
CIRCUIT DEVICE AND DEVICE FOR  
TESTING SAME

Dated: September 20, 2005

Conf. No.: 1170

Adjustment date: 09/23/2005 EAYALEW1  
09/22/2005 EAYALEW1 00000137 191013 10063472  
01 FC:1202 -100.00 DP  
02 FC:1251 100.00 CR -20.00 DP

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA. 22313-1450

**AMENDMENT AND RESPONSE UNDER 37 C.F.R. §1.111**

Sir:

In response to an Office Action of the U.S. Patent and Trademark Office mailed on May 20, 2005, please amend the subject application as follows:

**Amendments to the Drawings** are reflected on page 2

**Amendments to the Claims** are reflected in the listing of claims, which begins on page 3 of this paper.

**Remarks** begin on page 10 of this paper.

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20.00 DP

**CERTIFICATE OF MAILING UNDER 37 C.F.R. §1.8(a)**

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on September 20, 2005.

Dated: September 20, 2005

Paul J. Esatto, Jr.

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